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22nd International Congress on X-Ray Optics and Microanalysis

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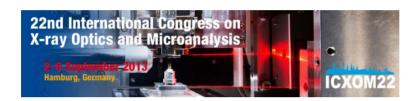
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Preface



The 22nd edition of the International Congress on X-ray Optics and Microanalysis (ICXOM 22) was held from 2–6 September 2013, in Hamburg, Germany. The congress was organized by scientists from DESY in collaboration with TU Dresden and Helmholtz-Zentrum Geesthacht, who also formed the scientific advisory board. The congress was hosted in the historical lecture hall building of the University of Hamburg located in the city center.

ICXOM22 was attended by about 210 registered participants, including 67 students, and was open for listeners. The attendance was split between 26 countries (Germany 120, rest of Europe 57, America 20, Asia 8, Australia 6).

The ICXOM series is a forum for the discussion of new developments in instrumentation, methods and applications in the fields of micro- and nano-analysis by means of X-ray beams. Following the trend of the last 10 years, the conference focusses more and more on synchrotron radiation rather than X-ray laboratory sources. Besides micro-beam X-ray fluorescence and absorption spectroscopy, different methods based on diffraction and full-field imaging were covered. Newly introduced to the ICXOM series was scanning coherent X-ray diffraction imaging, which was shown to evolve into a mature method for the imaging of nanostructures, defects and strain fields. New developments on fast X-ray detectors were discussed (*Lambda*, *Maia*) and advances in X-ray optics — like the generation of a sub 5nm point focus by Multilayer Zone plates — were presented. Talks on micro- and nano-analysis applications were distributed in special sessions on bio-imaging, Earth and environmental sciences, and Cultural heritage.

The congress featured nine keynote and ten plenary talks, 56 talks in 14 parallel sessions and about 120 posters in three afternoon sessions. Seventeen commercial exhibitors exposed related X-ray instrumentation products, and two luncheon seminars on detector electronics were given. This allowed us to keep the student fees low and to distribute eight student travel grants. The Wednesday was devoted to an outing to DESY with guided tours to PETRA III and FLASH experiments and to the European XFEL construction site. A lecture was given by Henry Chapman introducing to structural imaging at X-ray free-electron lasers. Talks highlighting the current status and future of nanoanalysis at the leading synchrotron facilities APS (J Maser), ESRF (P Cloetens) and SPRing8 (Ishikawa) were given in the DESY auditorium offering other DESY scientists the opportunity to follow the talks.

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Figure 1. Participants of ICXOM22 gathered in front of the main building of the University of Hamburg.

Further information about ICXOM22, including a detailed program and electronic abstract book, can be found on the congress website www.icxom22.de.

We thank all the participants of ICXOM22, everybody who helped in the organization and are looking forward to hearing about further progress during ICXOM23, which will be organized by Brookhaven National Laboratory in Uptown, New York.

Gerald Falkenberg ICXOM22 conference chair

Christian Schroer ICXOM22 co-chair